

**Search Notes**

Application/Control No.

10/662,560

Examiner

Alan S. Chen

Applicant(s)/Patent under  
Reexamination

HATANO, NAOYUKI

Art Unit

2182

**SEARCHED**

Class	Subclass	Date	Examiner
710	53	1/26/2006	ASC
N	54		
	55		
	56		
	57		
	62		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT PLUS; Inventor Search	9/15/2003	ASC